

Notice of References Cited	Application/Control No. 10/758,494	Applicant(s)/Patent Under Reexamination RHA ET AL.	
	Examiner W. David Coleman	Art Unit 2823	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Terry Barrette et al., "Evaluation of Early Failure Screening Mehtod"s, IEEE, 1996, pp. 14-17
	V	C. L. Henderson et al., "ICFAX, An Integrated Circuit Failure Analysis Expert System", IEEE,IRPS, 1991, pp. 142-151.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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